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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/811,915	03/19/2001	Wagdi W. Abadeer	BUR920000082US1(13647)	8953

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EXAMINER

NGUYEN, VINH P

ART UNIT

PAPER NUMBER

2829

DATE MAILED: 11/25/2002

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	Application No. 09/811,915	Applicant(s) ABADEER ET AL. N	
	Examiner VINH P NGUYEN	Art Unit 2829	

-- Th MAILING DATE of this communication app ars on th cov r sh t with the corr spond nce addr ss --
Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 17 September 2002.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 1-50 is/are pending in the application.
- 4a) Of the above claim(s) 17-20 and 42-46 is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☐ Claim(s) _____ is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on _____ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
- 11) ☐ The proposed drawing correction filed on _____ is: a) ☐ approved b) ☐ disapproved by the Examiner.
If approved, corrected drawings are required in reply to this Office action.
- 12) ☐ The oath or declaration is objected to by the Examiner.

Priority under 35 U.S.C. §§ 119 and 120

- 13) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
a) ☐ All b) ☐ Some * c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. _____.
3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
* See the attached detailed Office action for a list of the certified copies not received.
- 14) ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).
a) ☐ The translation of the foreign language provisional application has been received.
- 15) ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.

Attachment(s)

- | | |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413) Paper No(s). _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 3) <input checked="" type="checkbox"/> Information Disclosure Statement(s) (PTO-1449) Paper No(s) <u>4</u> | 6) <input type="checkbox"/> Other: _____ |

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1. Applicant's election of species of figure 3 includes claims 1-16,22-41 and 47-50 in Paper No. 6 is acknowledged. Because applicant did not distinctly and specifically point out the supposed errors in the restriction requirement, the election has been treated as an election without traverse (MPEP § 818.03(a)).

2. Claims 17-20,42-46 are withdrawn from further consideration pursuant to 37 CFR 1.142(b) as being drawn to a nonelected species, there being no allowable generic or linking claim. Election was made **without** traverse in Paper No. 6.

10/09/03
✓N
3. Claims 1-16,²²⁻⁴¹~~21-41~~ and 47-50 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.

In claim 1, it is unclear which device is used for performing the step of applying said voltage to at least one chip for the probing thereof in the absence of physically contacting the chip surface". It appears that the applied voltage has physical contact with the chip surface, therefore it is unclear how the step of magnetically inducing said voltage to said at least one chip ... is performed. Furthermore, it is unclear whether "a mask" has been positively claimed. In claim 10, it is unclear how this "said circuit" is interrelated and associated with "said circuit" in claim 5. It appears that the term "said circuit" in claim 5 is a different "said circuit" from the one in claim 10. In claim 25, it appears that the steps recited are not related to method for electrically stressing through a specified voltage at least one semiconductor chip on a wafer for controlled contactless burn-in, voltage screen and reliability evaluation of product wafer, therefore these

steps are improperly claimed, therefore they are not given any patentable weights. In claim 26, it is unclear whether "a mask" has been positively claimed. In claim 35, it is unclear how this "said circuit" is interrelated and associated with "said circuit" in claim 30. It appears that the term "said circuit" in claim 5 is a different "said circuit" from the one in claim 35. In claim 50, it appears that the steps recited are not related to method for electrically stressing through a specified voltage at least one semiconductor chip on a wafer for controlled contactless burn-in, voltage screen and reliability evaluation of product wafer, therefore these steps are improperly claimed, therefore they are not given any patentable weights.

4. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

5. Claims 1-3, and 26-28 (insofar as understood) are rejected under 35 U.S.C. 102(b) as being anticipated by Watanabe et al (Pat # 3,890,564).

As to claims 1, 5 and 26, Watanabe et al disclose an apparatus for inducing eddy current in a semiconductor wafer having magnetic cores (41,42) for magnetically inducing current flowing through the coils (11,13) to the wafer (S). It appears that the induced voltage would inherently created in the wafer when this induced current flowing through the wafer. As to claims 2-3 and 27-28, it appears that the induced voltage would inherently has those characteristics.


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6. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Ahrenkiel et al (Pat # 6,275,060) disclose apparatus and method for measuring minority carrier lifetimes in semiconductor materials.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to VINH P. NGUYEN whose telephone number is (703) 305-4914.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the Group receptionist whose telephone number is (703) 305-4900.


VINH P. NGUYEN
PRIMARY EXAMINER
ART UNIT 2829
11/21/2002